

**Notice of References Cited**

Application/Control No.

10/088,787

Applicant(s)/Patent Under  
Reexamination  
YUI ET AL.

Examiner

FADEY S. JABR

Art Unit

3628

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,665,397 A	05-1972	Di Napoli et al.	340/5.42
*	B	US-6,157,315 A	12-2000	Kokubo et al.	340/5.42
*	C	US-2001/0037174 A1	11-2001	Dickerson, Stephen L.	701/200
*	D	US-2001/0037298 A1	11-2001	Ehrman et al.	705/40
*	E	US-6,384,717 B1	05-2002	DeVolpi, Dean R.	340/432
*	F	US-2002/0186144 A1	12-2002	Meunier, Eric	340/825.28
*	G	US-6,696,981 B1	02-2004	Hashimoto, Hideki	340/988
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001188998 A	07-2001	Japan	NAMIKI, NORIO	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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